



Aalto University  
School of Engineering

# MEC-E6007

# Mechanical Testing of Materials

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*March 6, 2024*

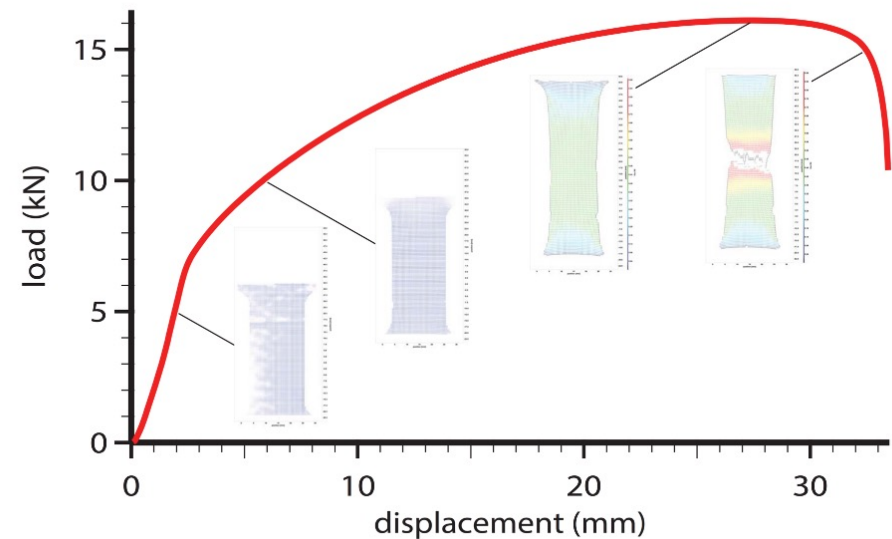


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# measuring force, strain, and displacement

# Course Content: *learning from breaking things*

- Load
  - loadframes, actuators, and grips
  - quasi-static, dynamic, and cyclic loading
- Measure
  - measurement of *force*, *displacement*, and *strain*
  - digital image correlation and other full-field measurement techniques
- Analyse
  - selected special challenges in mechanical testing (ask for yours!)
  - introduction to inverse problem methodologies in experimental mechanics



# measuring force

## definition of force:

- Newton's law
- $\text{force} = \text{mass} \times \text{acceleration}$ 
  - *e.g. weights*
  - *not practical for measurement*
  - *okay for calibration*

## Watt balance

- based on forces between wires carrying electrical current
- extremely precise measurement
  - *SI unit for mass to be redefined*

## Fluid pressure

## “dynamometer”

- Hooke's law
  - *ut tensio, sic vis*
- calibrated spring displacement proportional to force
  - *cantilever deflection for small forces*

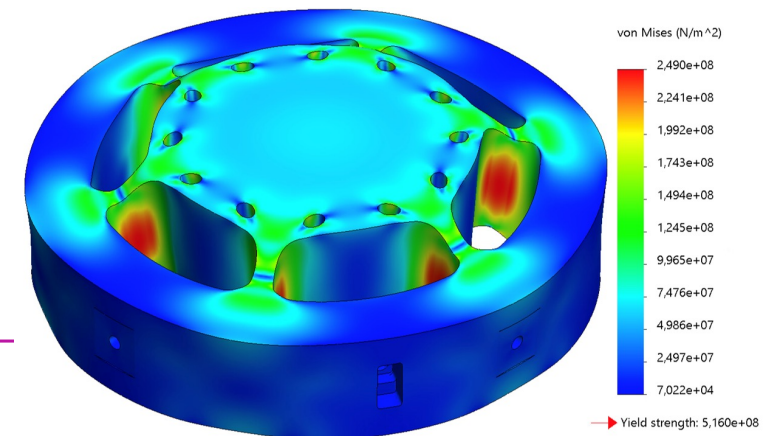
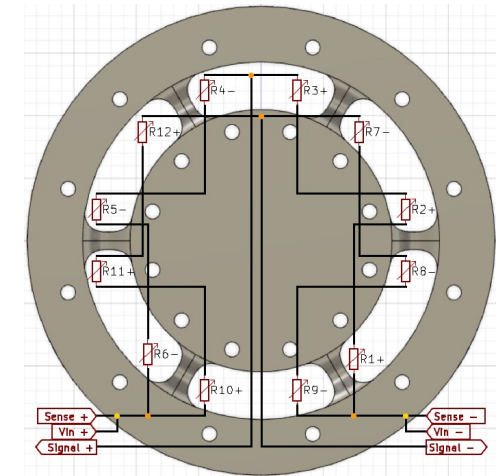
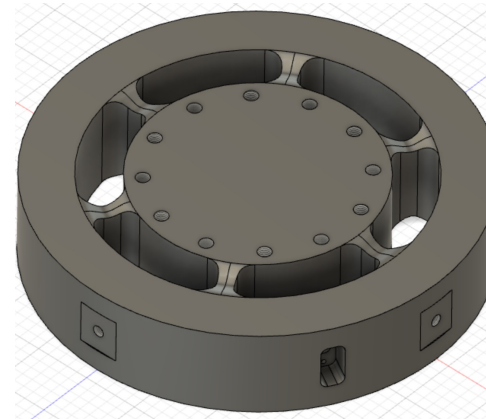
## special materials

- piezoelectric
- piezoresistive
- magnetostrictive
- photoelastic
- colour change

# Load cell

## mechanical amplification

- specially designed spring
  - *as stiff as possible*
  - *large strain in some parts*
  - *insensitive to other loads*
- electrical measurement of strain
  - *strain gauge or piezo-electric*
  - *temperature compensation*
- dynamic response
  - *usually limited by mechanical inertia*



# measuring position or displacement

## interferometry

- SI definition of meter
  - *count wavelengths*
  - *extremely sensitive*
- imaging interferometers
- speckle interferometry

## visual comparison

- calibrated ruler
  - *minimize parallax*
  - *vernier scale for enhanced precision*
- calibrated imaging geometry
  - *photogrammetry*
  - *stereo views for 3D displacement*
- optical position encoders

## mechanical amplification

- dial gauge
- clip gauge
- reflectometry

## integrate strain

- or use known conversion factor for local strain

## electrical capacitance

- inversely proportional to separation between conductive plates

## magnetic inductance

- Linear Variable Differential Transformer (LVDT)

## optical or electrical gates

- detect whether light or electricity can pass
  - *optionally measure how much*

## range-finding

- RADAR (radio waves)
- SONAR (sound)
- LIDAR (light)

## doppler effect

- sensitive to velocity differences
- integrate velocity over time

## inertial measurement

- accelerometers and gyroscopes
- integrate acceleration over time twice

# measuring strain

## definition of strain

- calculate from displacement gradient
- extensometers measuring relative displacement between ends of gauge length
- full-field strains from full-field displacement measurements

## diffraction

- specially designed fiber Bragg gratings
- atomic spacing from X-ray or neutron diffraction
- electron backscatter diffraction (EBSD) in scanning electron microscope (SEM)

## interferometry

- coherent gradient sensing (CGS)
- shearing speckle interferometry (shearography)

## moiré

- interference effect due to occlusion

## strain gauges

- resistivity changes due to conductor geometry change
  - *even larger change possible with piezoresistive effect*
- serpentine geometry sensitive in one direction

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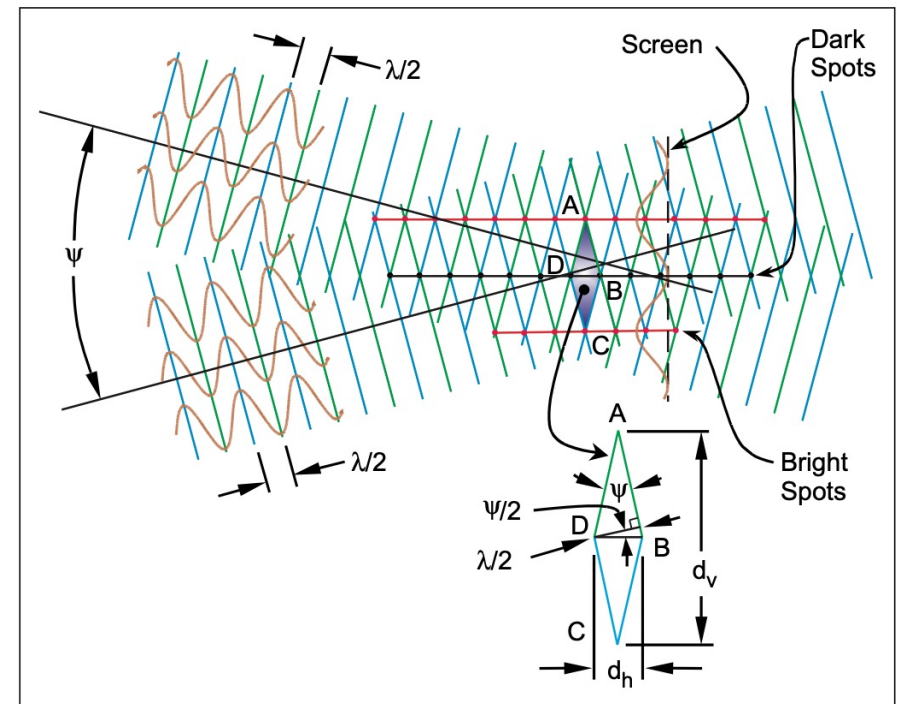
## percolation of conducting particles

- carbon-filled rubber
  - *widely used in old telephone sets*
- carbon nanofibers
- conductivity is extremely sensitive at percolation threshold
- electrical impedance tomography

# Interferometry

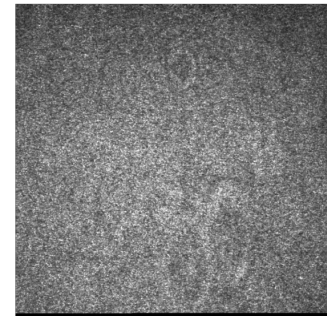
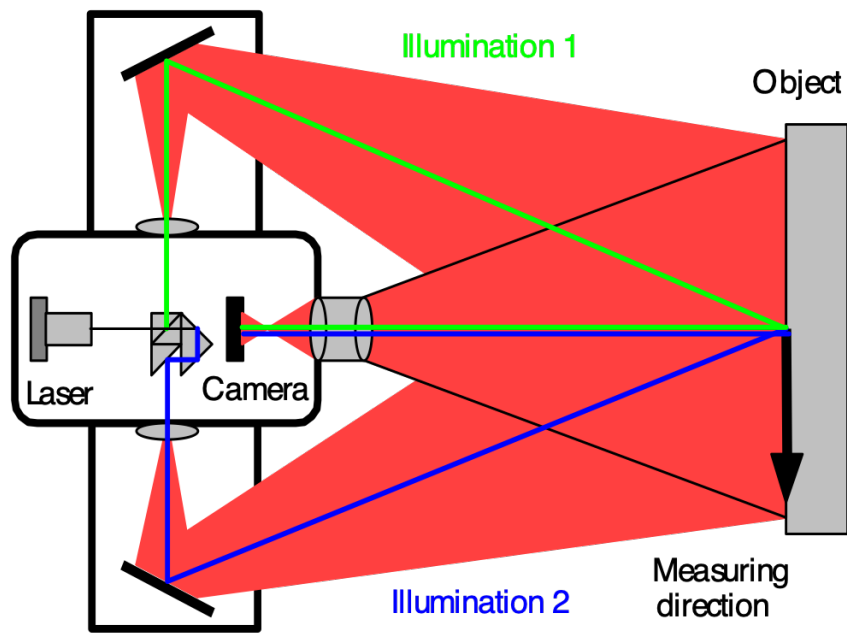
## coherent light

- positive or destructive interference depending on differential phase between two light paths originating from same source
- setup designed so displacement causes change in optical path length
- measurement precision is a fraction of the wavelength of the light used

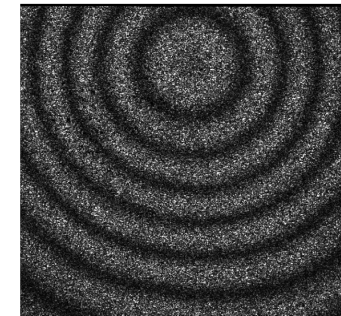




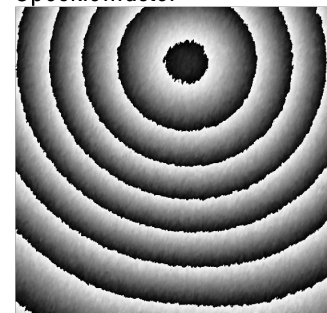
# Electronic Speckle Pattern Interferometry



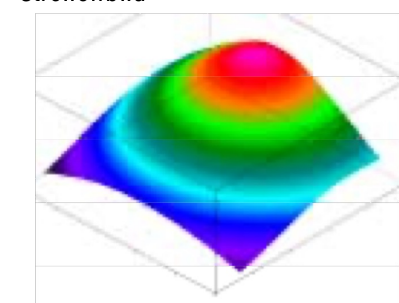
Specklemuster



Streifenbild

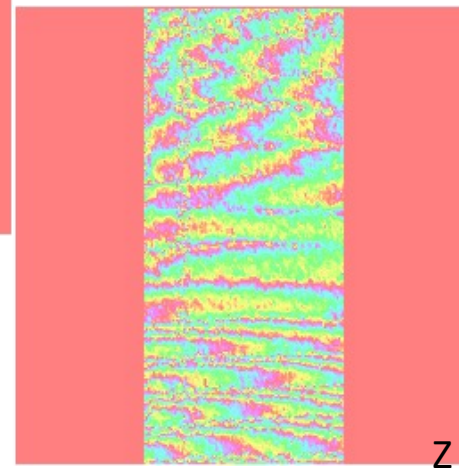
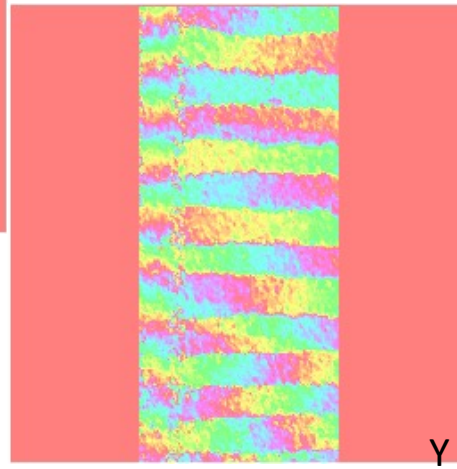
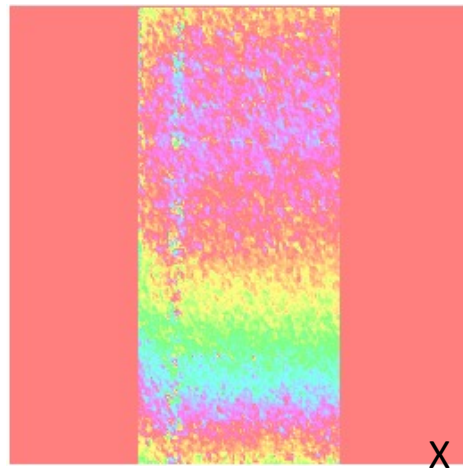


Phasenbild

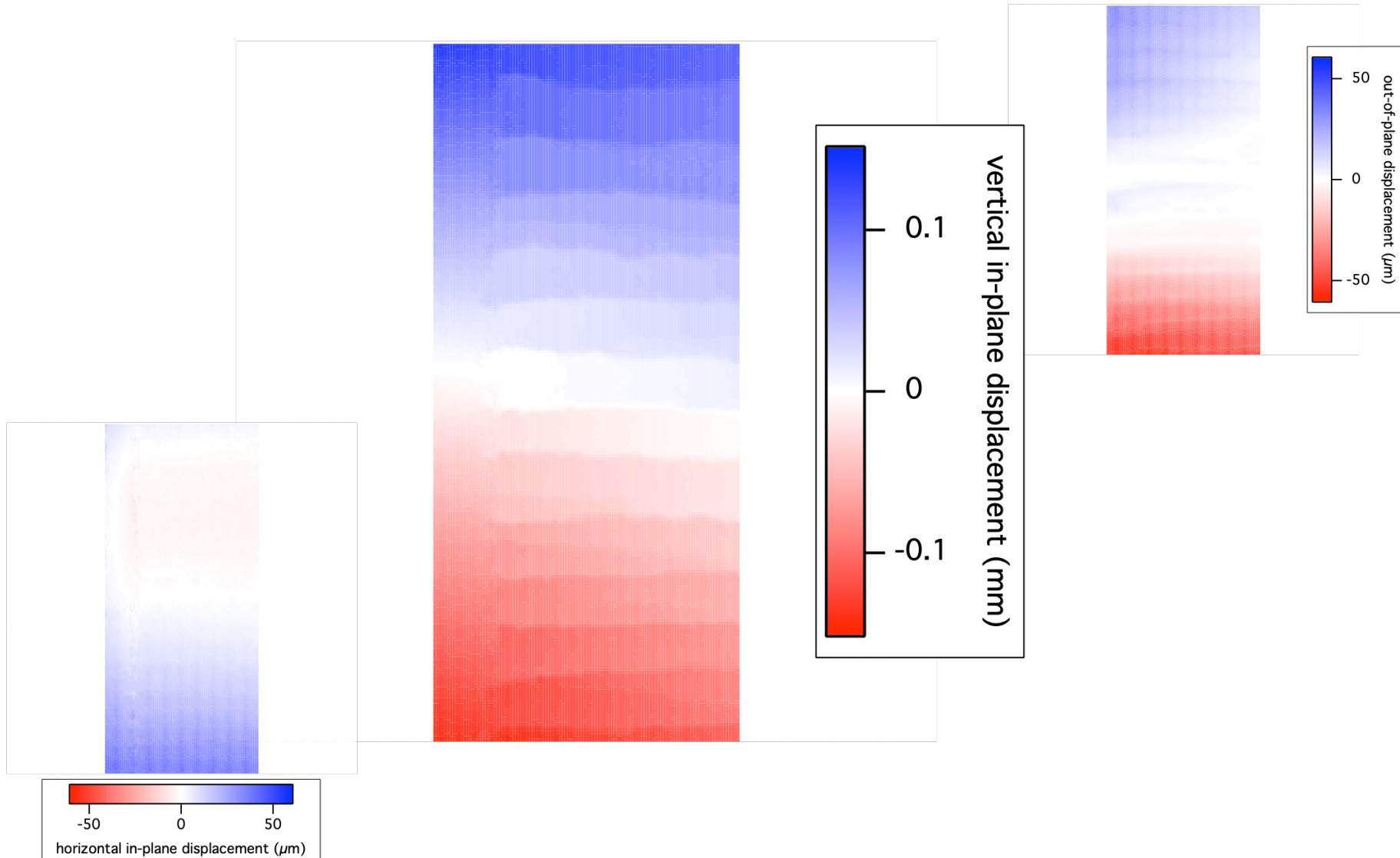


Verschiebungsfeld

# ESPI Phase Maps



# ESPI Displacement Fields



# Advantages and disadvantages of ESPI

## Advantages

- Very high sensitivity
  - *especially to out-of-plane motion*
- Direct measure of displacement
  - *lens distortions affect only location of the measurement, not displacement amplitude measured*

## Disadvantages

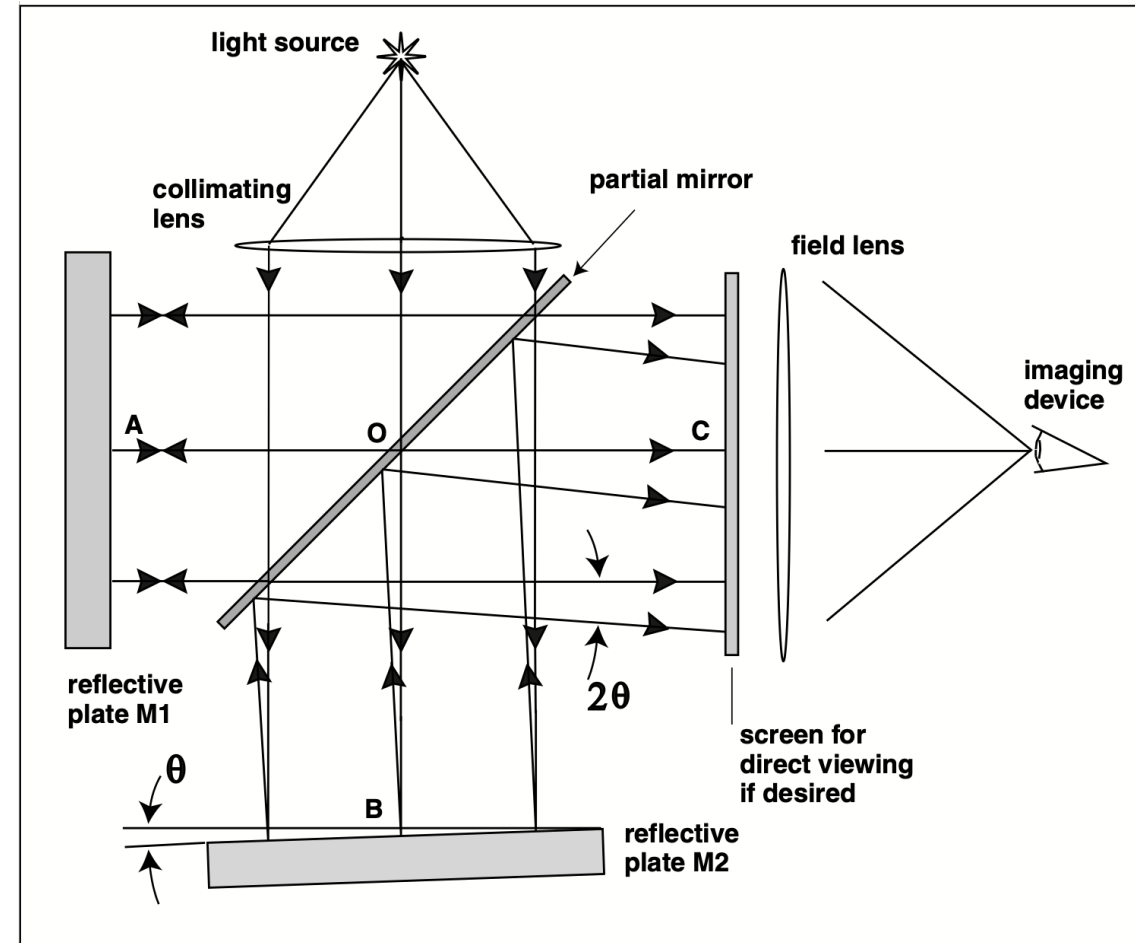
- Very high sensitivity
  - *especially to out-of-plane motion*
  - *vibrations!*
- Decoherence at large displacement amplitudes
- Coherent light needed

# Shearography

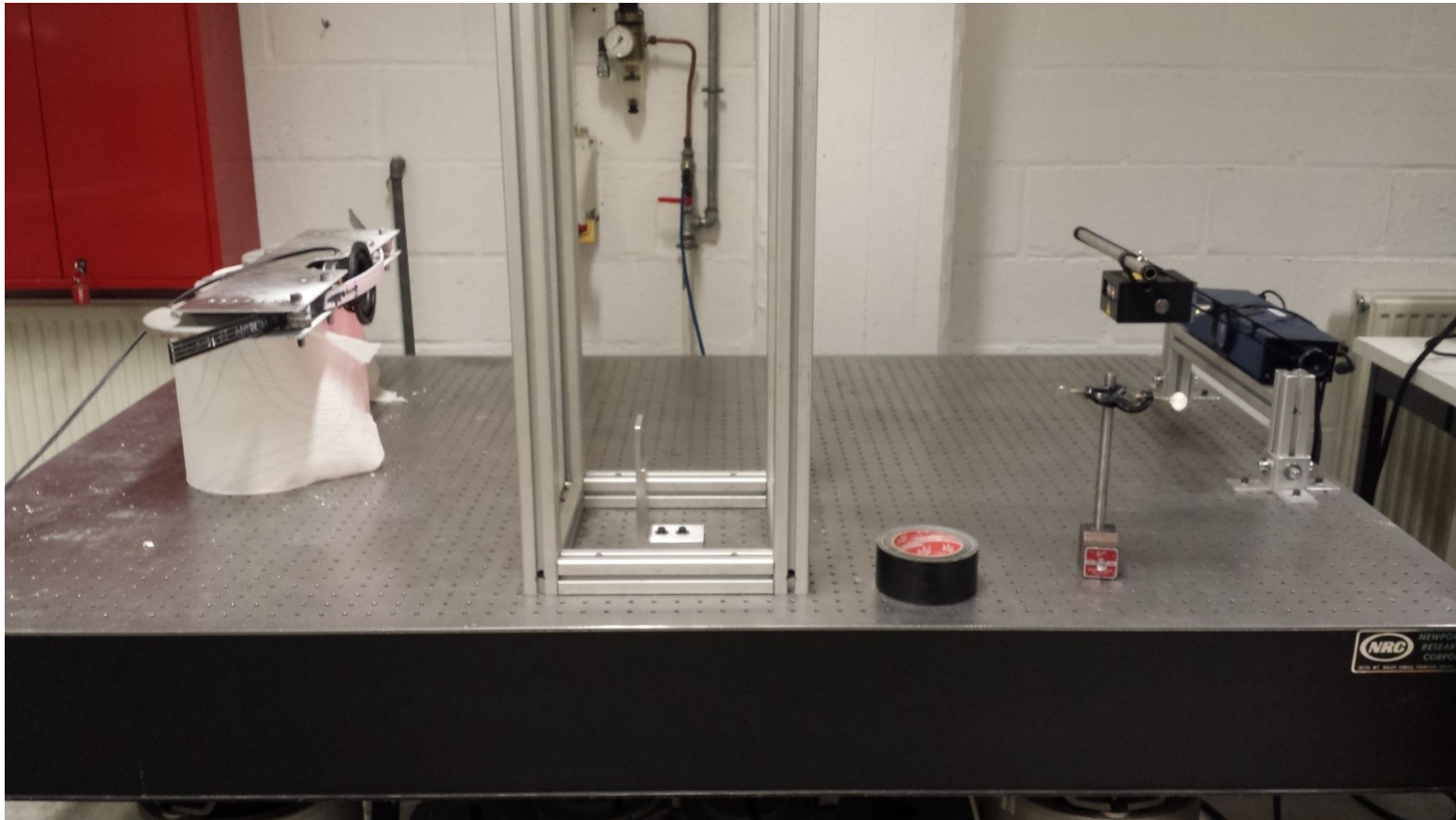
## “Misaligned” interferometer gives double image

Speckle Pattern Interferometry is then sensitive to displacement difference between two neighbouring points on the object

- More difficult to analyse quantitatively
- Less sensitive to vibrations

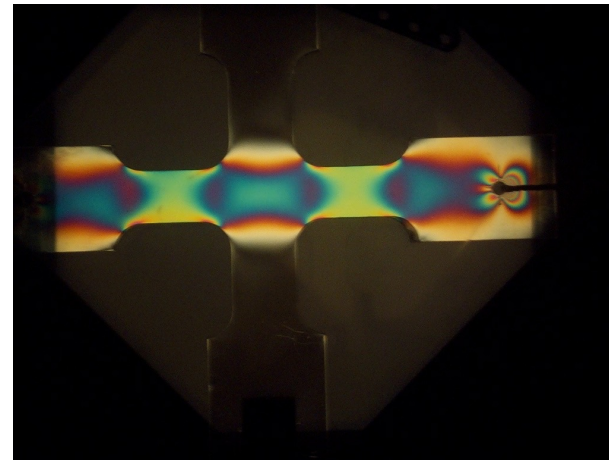
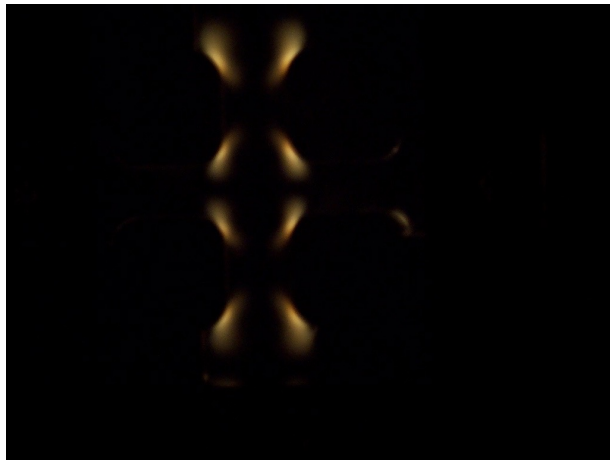
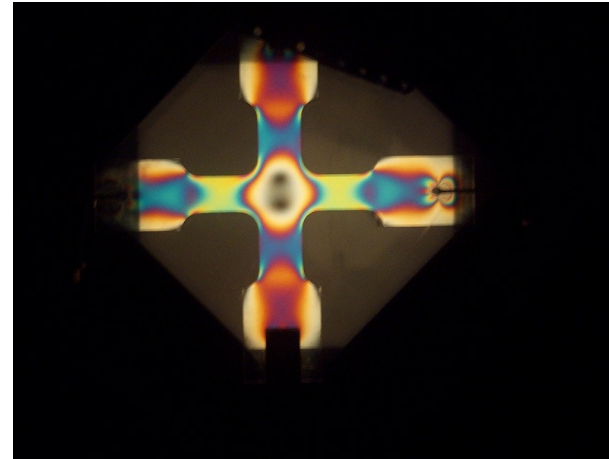
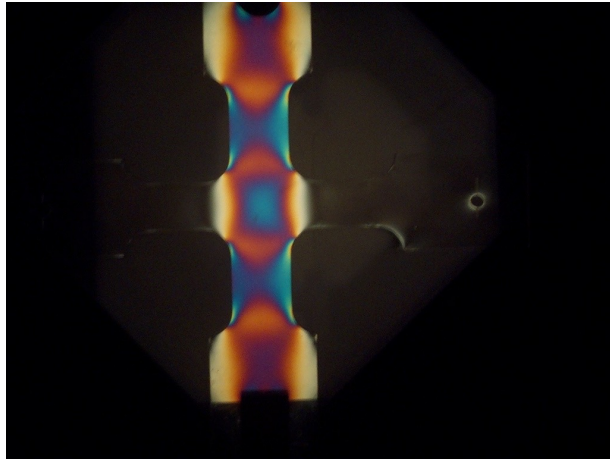


# Shearography example

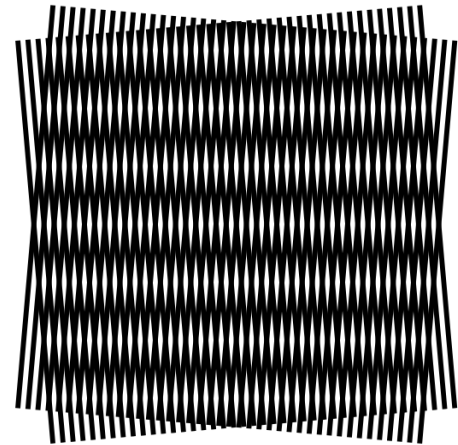
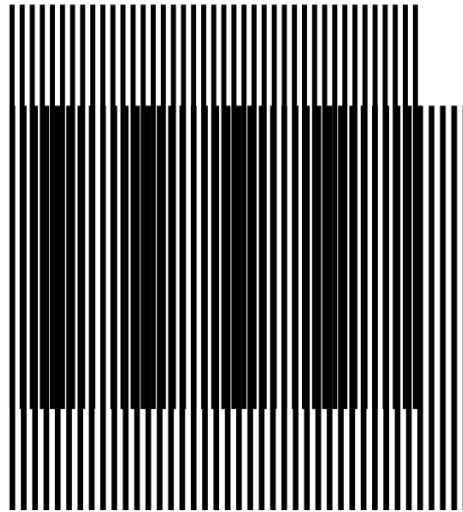
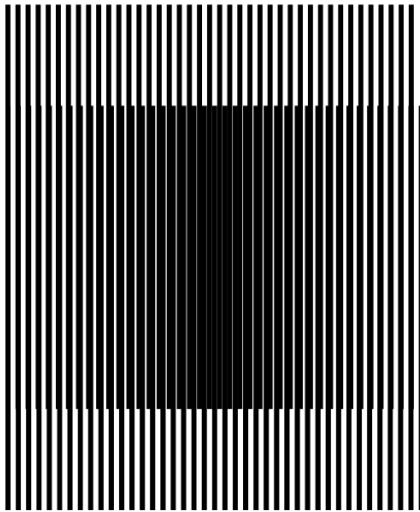




# Photoelasticity imaging birefringence with polarized light



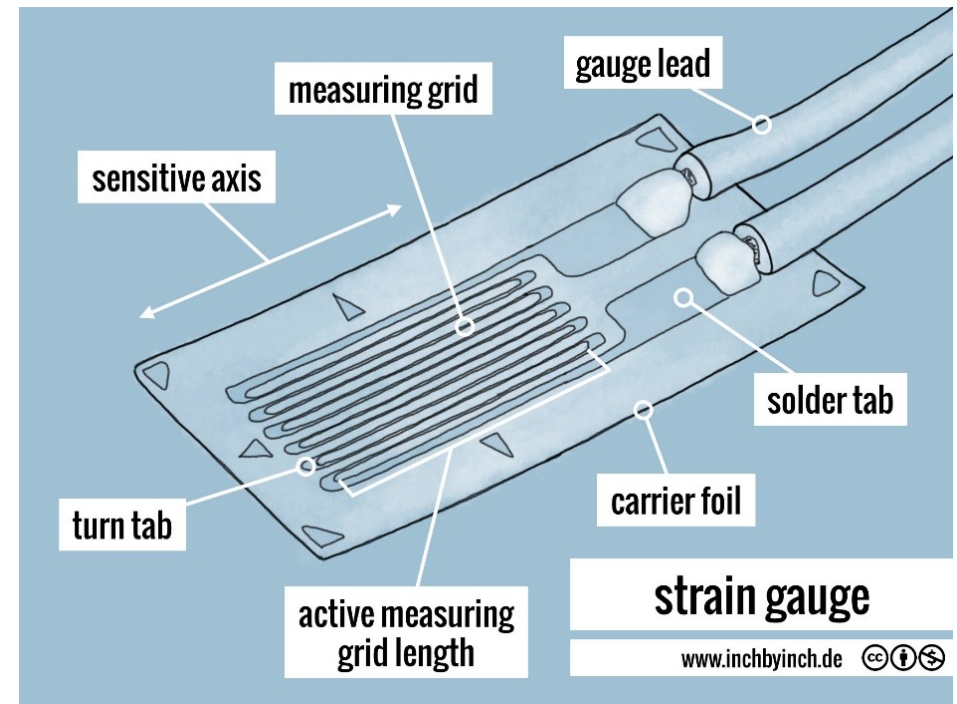
# Moiré





# Strain Gauges

- widely used in instrumentation
  - *e.g. most digital scales use strain gauges*
  - *usually in pairs or fours for differential measurements*
- bonded to surface
  - *need to choose appropriate glue*
- cable management
- rosette for calculating in-plane strain components
- Wheatstone bridge directly gives differential measurements



# electrical measurements and digital signal acquisition

## **ADC – Analog to Digital Conversion**

- fast dedicated circuitry to digitize voltages with high impedance
  - *other quantities amplified (or scaled down) to convert to 10V range*
  - *quantisation at a certain number of bits in the binary number*
  - *as expansion board in a computer or stand-alone*
- multiplexed to measure multiple channels in parallel
- care needed to ensure synchronous acquisition

## **coaxial cabling with standard connectors**

- shielding from electrical interference
- spurious signal transmission issues if cables kinked or crushed